•	High-Speed, Low-Skew 1-to-18 Clock Buffer for Synchronous DRAM (SDRAM) Clock		DL PACKAGE (TOP VIEW)				
	Buffering Applications			հ			
	Output Skew, t _{sk(o)} , Less Than 250 ps	NCL	1 48				
•	Pulse Skew, tek(p). Less Than 500 ps		2 47				
•	Supports up to Four Unbuffered SDRAM	V _{CC} L	3 46	L VCC			
	Dual Inline Memory Modules (DIMMs)	1Y0L	4 45				
	1 ² C Social Interface Provides Individual		5 44				
•	Frable Control for Each Output		6 43 7 40				
•			7 4Z				
•	Operates at 3.3 V	1/2	0 41				
•	Distributed V _{CC} and Ground Pins Reduce Switching Noise	GND	9 40 10 39	GND			
	100-MHz Operation	A	11 38	OE			
•		V _{CC}	12 37	V _{CC}			
•	ESD Protection Exceeds 2000 V Per	2Y0	13 36	3Y3			
	MIL-STD-883, Method 3015	2Y1	14 35	3Y2			
•	Packaged in 48-Pin Shrink Small Outline	GND	15 34	GND			
	(DL) Package	V _{CC}	16 33	Vcc			
		2Y2	17 32	3Y1			
descr	iption	2Y3	18 31	1 3Y0			
т	be CDC318A is a high-performance clock buffer	GND	19 30	GND			
d	esigned to distribute high-speed clocks in PC	V _{CC}	20 29	Vcc			
a	pplications. This device distributes one input (A)	5Y0	21 28	5Y1			
to	5 18 outputs (Y) with minimum skew for clock	GND	22 27	GND			
d	istribution. The CDC318A operates from a 3.3-V	V _{CC}	23 26	L GND			

NC - No internal connection

24

SDATA

25 SCLOCK

This device has been designed with consideration for optimized EMI performance. Depending on the application layout, damping resistors in series to the clock outputs (like proposed in the PC100 specification) may not be needed in most cases.

power supply. It is characterized for operation

from 0°C to 70°C.

The device provides a standard mode (100K-bits/s) I^2C serial interface for device control. The implementation is as a slave/receiver. The device address is specified in the I^2C device address table. Both of the I^2C inputs (SDATA and SCLOCK) are 5-V tolerant and provide integrated pullup resistors (typically 140 k Ω).

Three 8-bit I²C registers provide individual enable control for each of the outputs. All outputs default to enabled at powerup. Each output can be placed in a disabled mode with a low-level output when a low-level control bit is written to the control register. The registers are write only and must be accessed in sequential order (i.e., random access of the registers is not supported).

The CDC318A provides 3-state outputs for testing and debugging purposes. The outputs can be placed in a high-impedance state via the output-enable (OE) input. When OE is high, all outputs are in the operational state. When OE is low, the outputs are placed in a high-impedance state. OE provides an integrated pullup resistor.



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CDC318A 1-LINE TO 18-LINE CLOCK DRIVER WITH I²C CONTROL INTERFACE

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FUNCTION TABLE							
INP	UTS	OUTPUTS					
OE	Α	1Y0–1Y3	2Y0-2Y3	3Y0-3Y3	4Y0-4Y3	5Y0-5Y1	
L	Х	Hi-Z	Hi-Z	Hi-Z	Hi-Z	Hi-Z	
Н	L	L	L	L	L	L	
Н	Н	Hţ	H‡	H‡	H‡	H‡	

[†] The function table assumes that all outputs are enabled via the appropriate I²C configuration register bit. If the output is disabled via the appropriate configuration bit, then the output is driven to a low state, regardless of the state of the A input.

logic diagram (positive logic)





Terminal Functions

TERMINAL				
NAME	NO.	1/0	DESCRIPTION	
1Y0-1Y3	4, 5, 8, 9	0	3.3-V SDRAM byte 0 clock outputs	
2Y0-2Y3	13, 14, 17, 18	0	3.3-V SDRAM byte 1 clock outputs	
3Y0-3Y3	31, 32, 35, 36	0	3.3-V SDRAM byte 2 clock outputs	
4Y0-4Y3	40, 41, 44, 45	0	3.3-V SDRAM byte 3 clock outputs	
5Y0-5Y1	21, 28	0	3.3-V clock outputs provided for feedback control of external phase-locked loops (PLLs)	
А	11	I	Clock input	
OE	38	Į	Output enable. When asserted, OE puts all outputs in a high-impedance state. A nominal 140 -k Ω pullup resistor is internally integrated.	
SCLOCK	25	I	I ² C serial clock input. A nominal 140-kΩ pullup resistor is internally integrated.	
SDATA	24	I/O	Bidirectional I ² C serial data input/output. A nominal 140-k Ω pullup resistor is internally integrated.	
GND	6, 10, 15, 19, 22, 26, 27, 30, 34, 39, 43		Ground	
NC	1, 2, 47, 48		No internal connection. Reserved for future use.	
VCC	3, 7, 12, 16, 20, 23, 29, 33, 37, 42, 46		3.3-V power supply	

I²C DEVICE ADDRESS

A7	A6	A5	A4	A3	A2	A1	A0 (R/W)
Н	Н	L	Н	L	L	Н	—

I²C BYTE 0-BIT DEFINITION[†]

BIT	DEFINITION	DEFAULT VALUE
7	2Y3 enable (pin 18)	Н
6	2Y2 enable (pin 17)	Н
5	2Y1 enable (pin 14)	Н
4	2Y0 enable (pin 13)	Н
3	1Y3 enable (pin 9)	Н
2	1Y2 enable (pin 8)	Н
1	1Y1 enable (pin 5)	Н
0	1Y0 enable (pin 4)	Н

[†] When the value of the bit is high, the output is enabled. When the value of the bit is low, the output is forced to a low state. The default value of all bits is high.



	-	-
BIT	DEFINITION	DEFAULT VALUE
7	4Y3 enable (pin 45)	Н
6	4Y2 enable (pin 44)	Н
5	4Y1 enable (pin 41)	Н
4	4Y0 enable (pin 40)	Н
3	3Y3 enable (pin 36)	Н
2	3Y2 enable (pin 35)	Н
1	3Y1 enable (pin 32)	Н
0	3Y0 enable (pin 31)	Н

I²C BYTE 1-BIT DEFINITION[†]

[†]When the value of the bit is high, the output is enabled. When the value of the bit is low, the output is forced to a low state. The default value of all bits is high.

BIT	DEFINITION	DEFAULT VALUE
7	5Y1 enable (pin 28)	Н
6	5Y0 enable (pin 21)	Н
5	Reserved	Н
4	Reserved	Н
3	Reserved	Н
2	Reserved	Н
1	Reserved	Н
0	Reserved	Н

I²C BYTE 2-BIT DEFINITION[†]

[†]When the value of the bit is high, the output is enabled. When the value of the bit is low, the output is forced to a low state. The default value of all bits is high.



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC}	0.5 V to 4.6 V
	0.5 V to 4.6 V
Input voltage range, VI (SCLOCK, SDAIA) (see Note 1)	–0.5 V to 6.5 V
Output voltage range, V _O (SDATA) (see Note 1)	–0.5 V to 6.5 V
Voltage range applied to any output in the high or power-off state, V_O	\dots -0.5 V to V _{CC} +0.5 V
Current into any output in the low state (except SDATA), IO	48 mA
Current into SDATA in the low state, IO	12 mA
Input clamp current, I _{IK} (V _I < 0) (SCLOCK)	–50 mA
Output clamp current, I _{OK} (V _O < 0) (SDATA)	–50 mA
Package thermal impedance, θ_{JA} (see Notes 2 and 3)	84°C/W
Storage temperature range, T _{stg}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed. 2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51, except for through-hole packages,

which use a trace length of zero. The absolute maximum power dissipation allowed at TA = 55°C (in still air) is 1.2 W.

3. Thermal impedance (OIA) can be considerably lower if the device is soldered on the PCB board with a copper layer underneath the package. A simulation on a PCB board (3 in. × 3 in.) with two internal copper planes (1 oz. cu, 0.036 mm thick) and 0.071 mm cu (202) in area underneath the package, resulted in $\Theta_{JA} = 60^{\circ}$ C/W. This would allow 1.2 W total power dissipation at TA = 70°C.

recommended operating conditions (see Note 4)

			MIN	TYP	MAX	UNIT
VCC	3.3-V core supply voltage		3.135		3.465	V
		A, OE	2		V _{CC} +0.3	V
VIH	High-level input voltage	SDATA, SCLOCK (see Note 3)	2.2		5.5	V
		A, OE	-0.3		0.8	V
VIL	Low-level input voltage	SDATA, SCLOCK (see Note 3)	0		1.04	V
ЮН	High-level output current	Y outputs			-36	mA
IOL	Low-level output current	Y outputs			24	mA
rj	Input resistance to V_{CC}	SDATA, SCLOCK (see Note 3)		140		kΩ
f(SCL)	SCLOCK frequency				100	kHz
^t (BUS)	Bus free time		4.7			μs
t _{su} (START)	START setup time		4.7			μs
^t h(START)	START hold time		4			μs
^t w(SCLL)	SCLOCK low pulse duration		4.7			μs
^t w(SCLH)	SCLOCK high pulse duration		4			μs
^t r(SDATA)	SDATA input rise time				1000	ns
^t f(SDATA)	SDATA input fall time				300	ns
t _{su} (SDATA)	SDATA setup time		250			ns
^t h(SDATA)	SDATA hold time		20			ns
t _{su} (STOP)	STOP setup time		4			μs
T _A	Operating free-air temperature		0		70	°C

NOTE 4: The CMOS-level inputs fall within these limits: V_{IH} min = $0.7 \times V_{CC}$ and V_{II} max = $0.3 \times V_{CC}$.



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT		
VIK	Input clamp voltage		V _{CC} = 3.135 V,	lı = –18 mA			-1.2	V	
∨он	High-level output voltage	Y outputs	V _{CC} = Min to Max,	$I_{OH} = -1 \text{ mA}$	V _{CC} – 0.1 V			V	
			V _{CC} = 3.135 V,	I _{OH} = -36 mA	2.4				
		Vautauta	V_{CC} = Min to Max,	I _{OL} = 1 mA			0.1		
Vai		roulpuis	V _{CC} = 3.135 V,	I _{OL} = 24 mA			0.4	V	
VOL	Low-level output voltage	CD ATA		I _{OL} = 3 mA			0.4	v	
		SDATA	VCC = 3.135 V	$I_{OL} = 6 \text{ mA}$			0.6		
		SDATA	V _{CC} = 3.135 V,	$V_{O} = V_{CC} MAX$			20	μΑ	
1	Lich lovel output ourrest		V _{CC} = 3.135 V,	$V_{O} = 2 V$	-54		-126		
ЮН	High-level output current	Y outputs	V _{CC} = 3.3 V,	V _O = 1.65 V		-92		mA	
			V _{CC} = 3.465 V,	V _O = 3.135 V	-21		-46		
			V _{CC} = 3.135 V,	$V_{O} = 1 V$	49		118		
IOL	Low-level output current	Y outputs	V _{CC} = 3.3 V,	V _O = 1.65 V		93		mA	
			V _{CC} = 3.465 V,	$V_{O} = 0.4 V$	24		53		
		А					5		
ЦН	High-level input current	OE	V _{CC} = 3.465 V,	$V_{I} = V_{CC}$			20	μA	
		SCLOCK, SDATA					20		
		А					-5		
ЦĽ	Low-level input current	OE	V _{CC} = 3.465 V,	$V_{I} = GND$	-10		-50	μA	
		SCLOCK, SDATA			-10		-50		
IOZ	High-impedance-state output	it current	V _{CC} = 3.465 V,	$V_{O} = 3.465 \text{ V or } 0$			±10	μA	
loff	Off-state current	SCLOCK, SDATA	V _{CC} = 0,	$V_I = 0 V$ to 5.5 V			50	μA	
ICC	Supply current		V _{CC} = 3.465 V,	IO = 0		0.2	0.5	mA	
∆ICC	CC Change in supply current		$V_{CC} = 3.135$ V to 3.46 One input at $V_{CC} = 0$. All other inputs at V_{CC}	65 V, .6 V, _C or GND			500	μΑ	
	Dynamic I _{CC} at 100 MHz		V _{CC} = 3.465 V,	C _L = 20 pF,		230		mA	
Cl	Input capacitance		$V_{I} = V_{CC} \text{ or GND},$	$V_{CC} = 3.3 V$		4		pF	
CO	Output capacitance		$V_{O} = V_{CC} \text{ or } GND,$	V _C C = 3.3 V		6		pF	
CI/O	SDATA I/O capacitance		$V_{I/O} = V_{CC} \text{ or } GND,$	V _{CC} = 3.3 V		7		pF	



PARAMETER		FROM	то	TEST CONDITIONS	MIN	MAX	UNIT	
			А	Y		1.2	4.5	ns
^t PLH	Low-to-high level propagation delay time		SCLOCK↓	SDATA valid	V_{CC} = 3.3 V ±0.165 V, See Figure 3		2	μs
^t PLH	Low-to-high level propagation	delay time	SDATA↑	Y	V_{CC} = 3.3 V ±0.165 V, See Figure 3		150	ns
			А	Y		1.2	4.5	ns
^t PHL	High-to-low level propagation delay time		SCLOCK↓	SDATA valid	V_{CC} = 3.3 V ±0.165 V, See Figure 3		2	μs
^t PHL	High-to-low level propagation of	lelay time	SDATA↑	Y	$V_{CC} = 3.3 \text{ V} \pm 0.165 \text{ V},$ See Figure 3		150	ns
^t PZH	Enable time to the high level		OE Y	V		1	7	
t _{PZL}	Enable time to the low level				1 7	7	115	
^t PHZ	Disable time from the high leve		05	V		1	7	20
^t PLZ	Disable time from the low level		UE	ř		1	7	ns
^t sk(o)	Skew time		А	Y			250	ps
^t sk(p)	Skew time		А	Y			500	ps
^t sk(pr)	Skew time		А	Y			1	ns
t _r	Rise time			Y		0.5	2.2	ns
	Rise time (see Note 5 and	CD ATA			C _L = 10 pF	6		~~~
۲ŗ	Figure 3)	SDATA			CL = 400 pF		950	ns
t _f	Fall time			Y		0.5	2.3	ns
	Fall time (see Note 5 and	00.171			C _L = 10 pF	20		
ч	Figure 3)	SDATA			C _L = 400 pF		250	ns

switching characteristics over recommended operating conditions

NOTE 5: This parameter has a lower limit than BUS specification. This allows use of series resistors for current spike protection.

ESD information

ESD MODELS	LIMIT
Human Body Model (HBM)	2.0 kV
Machine Model (MM)	200 V
Charge Device Model (CDM)	2.0 kV

thermal information

		THE					
	CDC318A 48-PIN SSOP	0	150	250	500	UNIT	
$R_{\theta JA}$	High K		62	56	54	51	°C/W
$R_{\theta JA}$	Low K		95	71	65	58	°C/W
$R_{\theta JC}$	High K	36					°C/W
R ₀ JC	Low K	38					°C/W



CDC318A 1-LINE TO 18-LINE CLOCK DRIVER WITH I²C CONTROL INTERFACE

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PARAMETER MEASUREMENT INFORMATION

NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns. D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION



NOTES: A. Output skew, $t_{Sk(0)}$, is calculated as the greater of:

- The difference between the fastest and slowest of tpLHn (n = 1:18)
- The difference between the fastest and slowest of t_{PHLn} (n = 1:18)
- B. Pulse skew, $t_{sk(p)}$, is calculated as the greater of $|t_{PLHn} t_{PHLn}|$ (n = 1:18)
- C. Process skew, $t_{sk(pr)}^{(i)}$, is calculated as the greater of:
 - The difference between the fastest and slowest of tPLHn (n = 1:18) across multiple devices under identical operating conditions
 - The difference between the fastest and slowest of tPHLn (n = 1:18) across multiple devices under identical operating conditions

Figure 2. Waveforms for Calculation of t_{sk(o)}, t_{sk(p)}, t_{sk(pr)}



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PARAMETER MEASUREMENT INFORMATION



NOTES: A. The repeat start condition is not supported.

B. All input pulses are supplied by generators having the following characteristics: PRR \leq 100 kHz, Z_O = 50 Ω , t_r \geq 10 ns, t_f \geq 10 ns.

Figure 3. Propagation Delay Times, tr and tf





13-Oct-2016

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
CDC318ADL	ACTIVE	SSOP	DL	48	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	0 to 70	CDC318A	Samples
CDC318ADLG4	ACTIVE	SSOP	DL	48	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	0 to 70	CDC318A	Samples
CDC318ADLR	ACTIVE	SSOP	DL	48	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	0 to 70	CDC318A	Samples
CDC318ADLRG4	ACTIVE	SSOP	DL	48	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	0 to 70	CDC318A	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

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Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.



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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION

REEL DIMENSIONS

Texas Instruments





TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

TAPE AND REEL INFORMATION

*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDC318ADLR	SSOP	DL	48	1000	330.0	32.4	11.35	16.2	3.1	16.0	32.0	Q1

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PACKAGE MATERIALS INFORMATION

14-Jul-2012



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDC318ADLR	SSOP	DL	48	1000	367.0	367.0	55.0

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